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标题: Nonlinear optical THz generation and sensing applications

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摘要: We have suggested a wide range of real-life applications using novel terahertz imaging techniques. A high-resolution terahertz tomography was demonstrated by ultra short terahertz pulses using optical fiber and a nonlinear organic crystal. We also report on the thickness measurement of very thin films using high-sensitivity metal mesh filter. Further we have succeeded in a non-destructive inspection that can monitor the soot distribution in the ceramic filter using millimeter-to-terahertz wave computed tomography. These techniques are directly applicable to the non-destructive testing in industries.

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